

UNISONIC TECHNOLOGIES CO., LTD

4N100-FCQ Preliminary Power MOSFET

4A, 1000V N-CHANNEL POWER MOSFET

DESCRIPTION

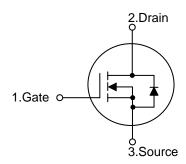
The UTC **4N100-FCQ** provide excellent $R_{DS(ON)}$, low gate charge and operation with low gate voltages. This device is suitable for use as a load switch or in PWM applications.

■ FEATURES

- * $R_{DS(ON)} \le 6.7 \Omega$ @ $V_{GS}=10V$, $I_D=1.0A$
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

TO-220F1 TO-220F1 TO-220F2 TO-251 TO-252

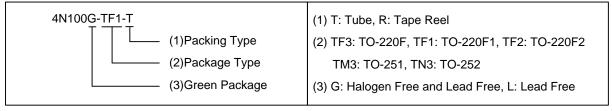
■ SYMBOL



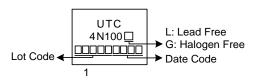
■ ORDERING INFORMATION

Ordering Number		Daakawa	Pin Assignment			Dankina	
Lead Free	Halogen Free	Package	1	2	3	Packing	
4N100L-TF1-T	4N100G-TF1-T	TO-220F1	G	D	S	Tube	
4N100L-TF2-T	4N100G-TF2-T	TO-220F2	G	D	S	Tube	
4N100L-TF3-T	4N100G-TF3-T	TO-220F	G	D	S	Tube	
4N100L-TM3-T	4N100G-TM3-T	TO-251	G	D	S	Tube	
4N100L-TN3-R	4N100G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING



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■ **ABSOLUTE MAXIMUM RATINGS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	1000	V
Gate-Source Voltage		V_{GSS}	±30	V
Continuous Drain Current		I _D	4	Α
Pulsed Drain Current (Note 2)		I _{DM}	8	Α
Avalanche Energy (Note 3)	Single Pulsed	E _{AS}	126	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	2.7	V/ns
Power Dissipation (T _A =25°C)	TO-220F/TO-220F1 TO-220F2	P _D	20	W
	TO-251/TO-252		45	W
Junction Temperature		TJ	+150	°C
Storage Temperature		T _{STG}	-55 ~ + 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=30mH, I_{AS} =2.9A, V_{DD} =100V, R_{G} =25 Ω , Starting T_{J} = 25°C
- 4. $I_{SD} \le 4.0A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER		SYMBOL	RATING	UNIT
Junction to Ambient	TO-220F/TO-220F1 TO-220F2	θЈΑ	62.5	°C/W
	TO-251/TO-252		110	°C/W
Junction to Case	TO-220F/TO-220F1 TO-220F2	θјс	6.25	°C/W
	TO-251/TO-252		2.7 (Note)	°C/W

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

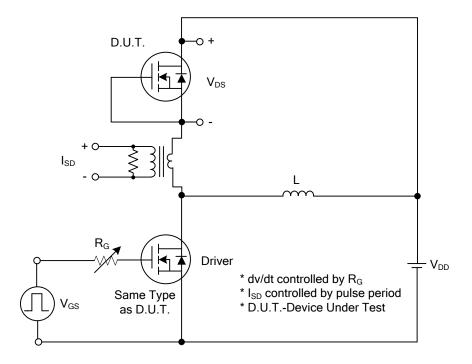
■ **ELECTRICAL CHARACTERISTICS** (T_J=25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	1000			V
Drain-Source Leakage Current		I _{DSS}	$V_{DS} = 1000V, V_{GS} = 0V$			10	μΑ
Gate-Source Leakage Current	Forward	- I _{GSS}	$V_{GS} = 30V, V_{DS} = 0V$			100	nΑ
	Reverse		$V_{GS} = -30V, V_{DS} = 0V$			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	$V_{GS} = 10V, I_D = 1.0A$			6.7	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance	nput Capacitance				520		pF
Output Capacitance		Coss	$V_{DS} = 25V, V_{GS} = 0V, f = 1MHz$		49		pF
Reverse Transfer Capacitance		C _{RSS}			1.9		pF
SWITCHING CHARACTERISTICS	S						
Total Gate Charge		Q_G	\/ 800\/ \/ 10\/ 40		9		nC
Gate-Source Charge		Q_GS	V _{DS} =800V, V _{GS} =10V, I _D =4A, I _G =1mA (Note 1, 2)		4.6		nC
Gate-Drain Charge		Q_GD	IG= IIIIA (Note 1, 2)		0.5		nC
Turn-On Delay Time		t _{D (ON)}			9		ns
Turn-On Rise Time		t _R	$V_{DD} = 100V, V_{GS} = 10V, I_{D} = 4A,$		15		ns
Turn-Off Delay Time		t _{D(OFF)}	R _G =25Ω (Note 1, 2)		18		ns
Turn-Off Fall Time		t _F			28		ns
DRAIN-SOURCE DIODE CHARA	CTERISTIC	CS					
Maximum Body-Diode Continuous Current		Is				4	Α
Continuous Drain-Source Current		I _{SD}				8	Α
Drain-Source Diode Forward Voltage		V_{SD}	I _S =4A, V _{GS} =0V			1.4	V
Reverse Recovery Time		t _{rr}	1 4 4 di/dt = 100 A /u.c		480		ns
Reverse Recovery Charge		Q _{rr}	I _F =4A, di/dt = 100A/μs		7.2		μC

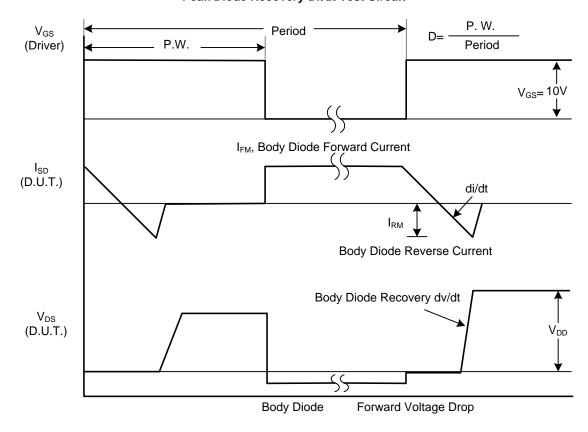
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤2%.

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

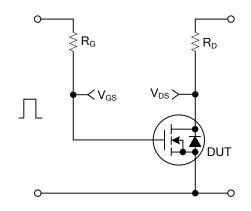


Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

■ TEST CIRCUITS AND WAVEFORMS



90%

10%

V_{GS}

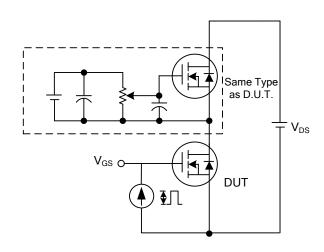
10%

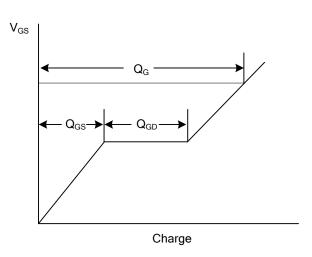
t_{d(ON)} t_R

t_{OFF}

itching Test Circuit

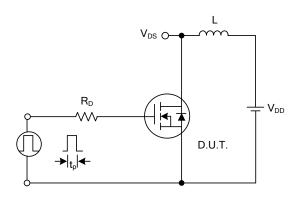
Switching Waveforms

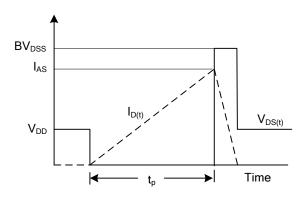




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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